

FDMS7570S-VB Datasheet N-Channel 30 V (D-S) MOSFET

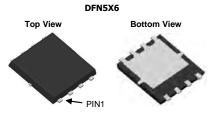
PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, e}	Q _g (Typ.)			
30	0.0018 at V _{GS} = 10 V	160	82 nC			
	0.0025 at V _{GS} = 4.5 V	130	02 110			

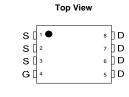
FEATURES

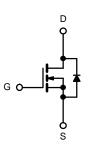
- Trench Power MOSFET
- 100 % R_g and UIS Tested

APPLICATIONS

- OR-ing
- Server ٠







RoHS COMPLIANT

N-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	± 20	v
	T _C = 25 °C		160 ^{a, e}	
Continuous Drain Current (T _J = 175 °C)	T _C = 70 °C		90 ^e	
Continuous Drain Current (1) = 175 C)	T _A = 25 °C	I _D	33 ^{b, c}	Α
	T _A = 70 °C		29.8 ^{b, c}	
Pulsed Drain Current	I _{DM}	300		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	36	
Single Pulse Avalanche Energy	L = 0.1 mm	E _{AS}	64.8	mJ
Continuous Source-Drain Diode Current	T _C = 25 °C	la	90 ^{a, e}	Α
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	3.13 ^{b, c}	A
	T _C = 25 °C		250 ^a	
Movimum Douge Discipation	T _C = 70 °C	P	175	w
Maximum Power Dissipation	T _A = 25 °C	P _D	3.75 ^{b, c}	vv
	T _A = 70 °C		2.63 ^{b, c}	
Operating Junction and Storage Temperature R	ange	T _J , T _{stg}	- 55 to 175	°C

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s		32	40	°C/W		
Maximum Junction-to-Case	Steady State R _{thJC} 0.5 0.6		0/10				

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under steady state conditions is 90 °C/W.

e. Calculated based on maximum junction temperature. Package limitation current is 90 A.

Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit
Static			•	•		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_D = 250 \mu A$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L = 250 µA		35		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 7.5		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	1.5		2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	90			А
		V _{GS} = 10 V, I _D = 32 A		0.0018		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 29 A		0.0025		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 32 A		160		S
Dynamic ^b						
Input Capacitance	C _{iss}				9900	pF
Output Capacitance	C _{oss}	V_{DS} = 12.5 V, V_{GS} = 0 V, f = 1 MHz			1725	
Reverse Transfer Capacitance	C _{rss}				970	
Total Gate Charge	Qg	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 32 \text{ A}$			83	nC
					82	
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 4.5 V, I_{D} = 29 A			34	
Gate-Drain Charge	Q _{gd}				29	
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω
Turn-On Delay Time	t _{d(on)}			18	27	ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.555 Ω		11	17	
Turn-Off Delay Time	t _{d(off)}	$I_{D} \cong$ 27 A, V_{GEN} = 10 V, R_{g} = 1 Ω		70	105	
Fall Time	t _f			10	15	
Turn-On Delay Time	t _{d(on)}			55	83	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		180	270	
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D}{\cong}24$ A, V_GEN = 4.5 V, R_g = 1 Ω		55	83	
Fall Time	t _f			12	18	
Drain-Source Body Diode Characteristic	s					
Continuous Source-Drain Diode Current	۱ _S	$T_{C} = 25 \ ^{\circ}C$			100	Δ
Pulse Diode Forward Current ^a	I _{SM}				200	
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 20 A, di/dt = 100 A/μs, Τ _{.1} = 25 °C		70.2	105	nC
Reverse Recovery Fall Time	t _a	F = 20 A, di/dl = 100 A/µs, $T = 25 C$		27		
Reverse Recovery Rise Time	t _b			25		ns

Notes:

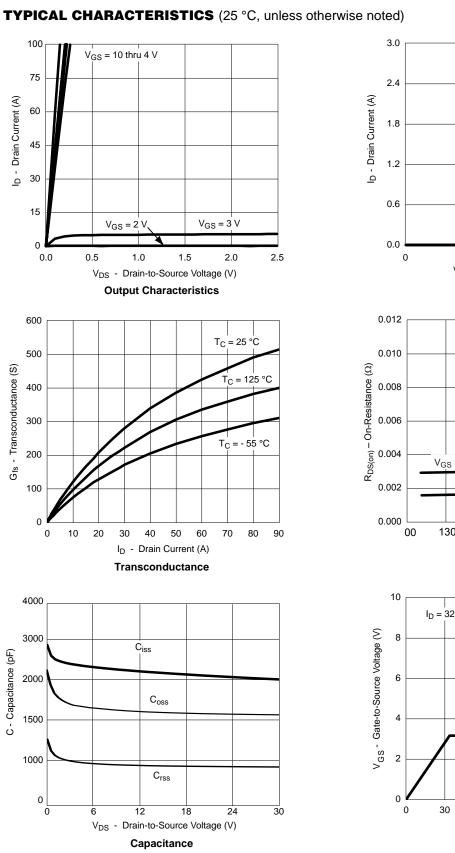
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

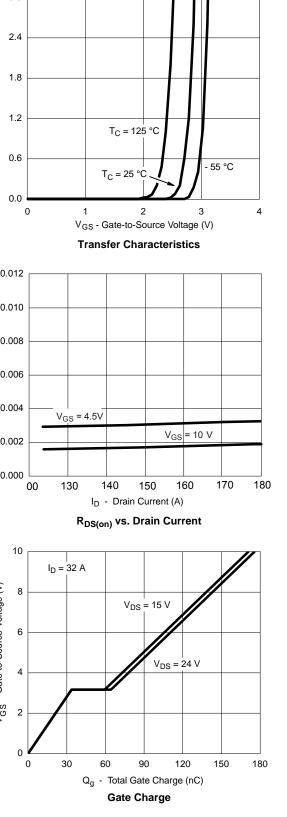
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Bsemi

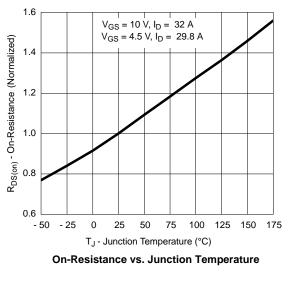
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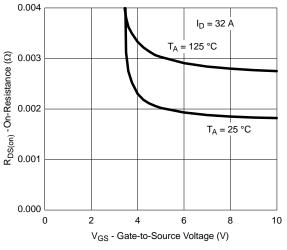




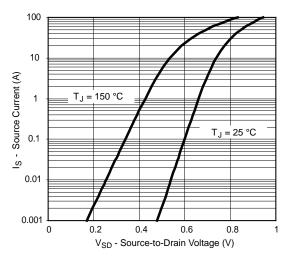




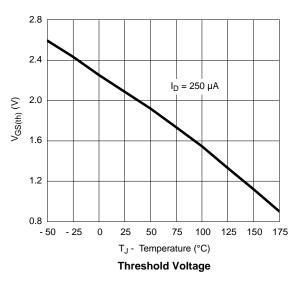
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

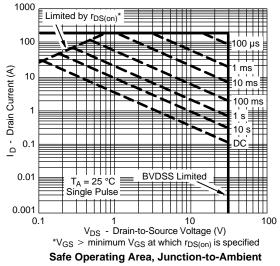


 $R_{\text{DS(on)}}$ vs. V_{GS} vs. Temperature

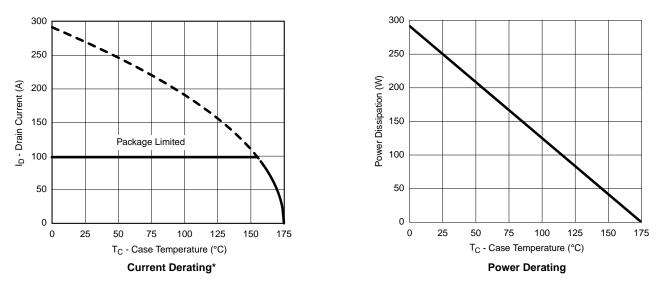


Forward Diode Voltage vs. Temperature



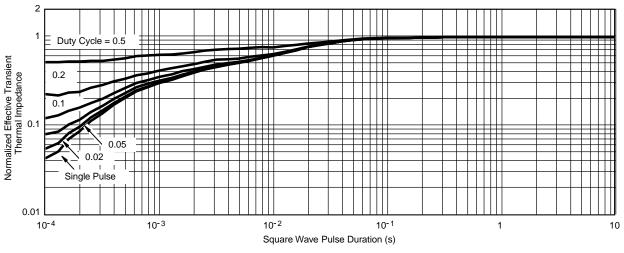






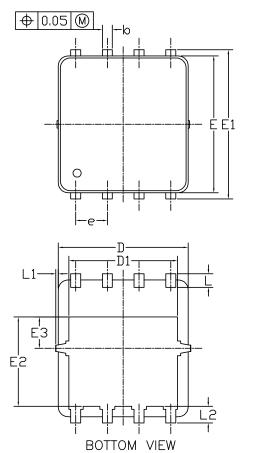
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

* The power dissipation P_D is based on $T_{J(max)}$ = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

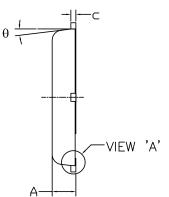


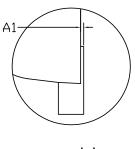
Normalized Thermal Transient Impedance, Junction-to-Case

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DFN5x6_8L_EP1_P PACKAGE OUTLIN





<u>VIEW 'A'</u> (SCALE 5:1)

RECOMMENDED LAND PATTERN .60 -0.55 0.50 -0.77 -0.635 4.12 6.15 -1.60 + + 0.65 +|+| ŧ 0.50--11.27-

SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES			
STINDOLS	MIN	NOM	MAX	MIN	NOM	MAX	
А	0.85	0.95	1.00	0.033	0.037	0.039	
Al	0.00		0.05	0.000		0.002	
b	0.30	0.40	0.50	0.012	0.016	0.020	
с	0.15	0.20	0.25	0.006	0.008	0.010	
D	5.10	5.20	5.30	0.201	0.205	0.209	
D1	4.25	4.35	4.45	0.167	0.171	0.175	
E	5.45	5.55	5.65	0.215	0.219	0.222	
E1	5.95	6.05	6.15	0.234	0.238	0.242	
E2	3.525	3.625	3.725	0.139	0.143	0.147	
E3	1.175	1.275	1.375	0.046	0.050	0.054	
e	1.27 BSC			0.050 BSC			
L	0.45	0.55	0.65	0.018	0.022	0.026	
L1	0		0.15	0		0.006	
L2	0.68 REF			0.027 REF			
θ	0°		10°	0°		10°	

NOTE

UNIT: mm

 PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
CONTROLLING DIMENSION IS MILLIMETER.

CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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